**TOSHIBA** 

Unit in mm

TOSHIBA TRANSISTOR SILICON PNP EPITAXIAL TYPE (PCT PROCESS)

# 2 S A 1 2 9 7

### POWER AMPLIFIER APPLICATIONS

#### POWER SWITCHING APPLICATIONS

- Low Saturation Voltage :  $V_{CE (sat)} = -0.5V (Max.) @I_{C} = -2A$
- Complementary to 2SC3267.

## MAXIMUM RATINGS (Ta = 25°C)

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CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	$v_{\mathrm{CBO}}$	-20	V
Collector-Emitter Voltage	$v_{CEO}$	-20	V
Emitter-Base Voltage	$V_{EBO}$	6	V
Collector Current	$I_{\mathbf{C}}$	-2	Α
Base Current	$I_{\mathrm{B}}$	-0.5	A
Collector Power Dissipation	$P_{\mathbf{C}}$	400	mW
Junction Temperature	$T_{j}$	150	$^{\circ}\mathrm{C}$
Storage Temperature Range	$T_{ m stg}$	-55~150	$^{\circ}\mathrm{C}$

#### 4.2MAX. 0.55MAX. 0.4 0.4 0.55MAX. 0.4 0.55MAX. 0.4 0.4 0.55MAX. 0.4 0.55MAX. 0.55MAX

2. COLLECTOR

3. BASE

JEDEC

EIAJ

IAJ

TOSHIBA 2-4E1A

Weight: 0.13g

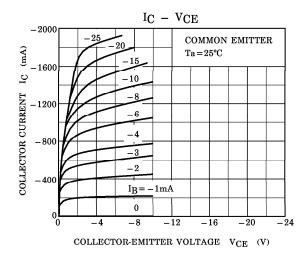
# ELECTRICAL CHARACTERISTICS (Ta = 25°C)

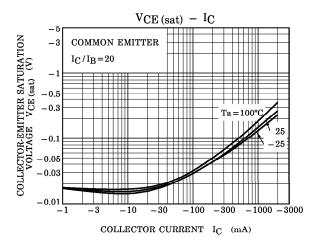
CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	$I_{CBO}$	$V_{CB} = -20V, I_{E} = 0$	_		-0.1	$\mu$ <b>A</b>
Emitter Cut-off Current	$I_{ m EBO}$	$V_{EB} = -6V, I_C = 0$	<b>—</b>	_	-0.1	$\mu$ <b>A</b>
Collector-Emitter Breakdown Voltage	V <sub>(BR)</sub> CEO	$I_{C} = -10 \text{mA}, I_{B} = 0$	-20	_	_	V
Emitter-Base Breakdown Voltage	V (BR) EBO	$I_E = -0.1 \text{mA}, I_C = 0$	-6	_	_	v
DC Current Gain	h <sub>FE (1)</sub> (Note)	$V_{CE} = -2V, I_{C} = -0.1A$	120	_	400	
	h <sub>FE</sub> (2)	$V_{CE} = -2V, I_{C} = -2A$	40	_	_	
Collector-Emitter Saturation Voltage	V <sub>CE</sub> (sat)	$I_C = -2A, I_B = -0.1A$	_	_	-0.5	V
Base-Emitter Voltage	$V_{ m BE}$	$V_{CE} = -2V, I_{C} = -0.1A$	_	_	-0.85	V
Transition Frequency	$f_{\mathrm{T}}$	$V_{CE} = -2V, I_{C} = -0.5A$	_	120	_	MHz
Collector Output Capacitance	C <sub>ob</sub>	$V_{CB} = -10V, I_E = 0, f = 1MHz$		40		pF

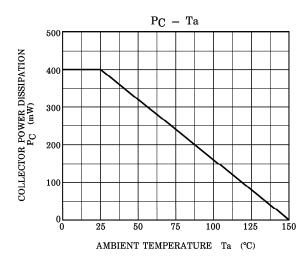
Note:  $h_{FE(1)}$  Y: 120~240, GR: 200~400

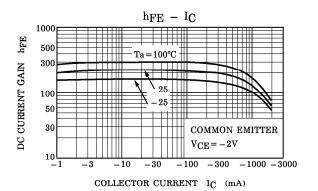
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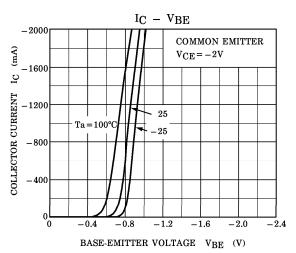
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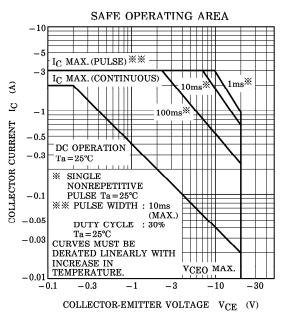












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